JPL PART #	MFG	MFG PART #	PACKAGE	DETAIL	ELECTRICAL	RADIATION
ST12142-			STYLE	SCREENING	CHARACTERISTICS &	(TID) LEVEL
			2/	TESTS	GROUP A TESTS	RAD(Si)
DN4614BR	MSC/KNX	1N4614-1	DO35	MIL-S-	MIL-S-195ØØ/435	1ØØk <u>3</u> /
through		through		195ØØ/435	(TABLE I)	
DN4627BR		1N4627-1				

NOTES:

- 1/ This drawing in conjunction with CS515581, imposes all requirements for procurement of these devices.
- 2/ Device physical dimensions shall conform to MIL-S-195ØØ/435, Figure 1a.
- 3/ Sufficient radiation tolerance to this TID level is guaranteed by design for this device. (See CS515581, Paragraph 4.7.7).
- 4. Final finish of leads shall be hot solder dip in accordance with MIL-S-195ØØ.
- 5. This standard takes precedence over documents referenced herein.

RELEASED THRU SE	CTION 356 DATA MANAGEMENT:	DATE:			
REVISION: B	APPROVED BY:	date: Ø9-16-92			
	APPROVED SOURCE(S)		THE ITEM LISTED IN THE APPROVED SOURCE BLOCK AND IDENTIFIED BY VENDOR NAME, ADDRESS, AND PART NUMBER WILL BE EVALUATED AND TESTED BY THE JPL ELECTRONIC PARTS RELIABILITY SECTION OR ITS DELEGATED ALTERNATE BEFORE BEING APPROVED FOR USE. NON-JPL USERS SHALL CHECK WITH THE ELECTRONIC PARTS RELIABILITY SECTION ON THE STATUS OF THE PART'S APPROVAL BEFORE USING.		
VENDOR PART NO	VENDOR	JPL PART NO			
JET PROP	ULSION LABORATORY CALIFORNIA INS	TITUTE OF TECHNOL	OGY CAGE NO 23835		
Procurement specification: CS515581 Screening specification: ZPP-2Ø73-GEN	TITLE: DIODE, SILICON, ZENE VOLTAGE REGULATOR, LOW NOI		DETAIL SPECIFICATION ST 12142		
Custodian: Electronic Parts	-		SHEET 1 OF 1		
Reliability Section 514			Piller I OI I		